CSIR - CENTRAL ELECTROCHEMICAL RESEARCH INSTITUTE
KARAIKUDI – 630 003
CENTRAL INSTRUMENTATION FACILITY DIVISION

Requisition form for XRD Analysis

1. **Name & Designation** :
2. **Institution name and Address** :
3. **Contact details (Email ID/ Mobile)** :
4. **Type of User** *(Tick the appropriate box)* : ☐ **Academic** ☐ **CSIR Lab** ☐ **R&D Institute** ☐ **Industry**
5. **Number of Sample(s)** :
6. **Preferred Technique & Sample information:** **(Kindly √ tick the appropriate box and fill the corresponding information)**

☐ **A) Normal Scan**
Scan Range (2ϑ) 5 – 90˚ & step size 6˚/ min

☐ **B) Slow Scan**
Scan Range (2ϑ) 5 – 90˚ & step size 3˚ / min

☐ **#C) SAXS (Low Angle)**
Scan Range (2ϑ) 1 – 10˚ with step size 1˚/ min

☐ **#D) Thin Film (GIXRD)**
Scan Range (2ϑ) 5 – 90˚ & step size 3˚ / min

☐ **#E) High Temperature XRD**

☐ **#F) 2D XRD**

Sample Code	Sample Type (Fine Powder / Solid / Thin Film)	Nature of Sample (Toxic/ Non-toxic/Corrosive/ Radioactive, etc.)**	Remarks

Undertaking

Certified that the above request is for academic/ research & development purpose (not for any legal disputes). Concessional charges may kindly be collected. Further certified that we will undertake guarantee for the payment of concessional charges.

Name & Signature of the User **Name & Signature of the Guide** **Signature of the HoD / Principal**

Date: **Seal** **Seal**

Charge per sample:

Technique	Charges in INR		
	For Industries	For R&D labs	For Academic Institutions / CSIR Labs
Normal Scan	2000.00	1000.00	500.00
Slow Scan	5200.00	2600.00	1300.00
Thin Film (GIXRD)	5200.00	2600.00	1300.00
High Temperature	8000.00	4000.00	2000.00
2D XRD	8000.00	4000.00	2000.00
SAXS (Small / Low Angle XRD)	16000.00	8000.00	4000.00

In addition to the Analytical Charges, Goods and Service Taxes (GST) is as applicable.

"For information to the users (do not print)."

* **Sample Requirement:**

- Fine Powder: Should be fine, with a quantity of 1 gm.
- Solid: Flat sample with a size of ≥ 10 mm to ≤ 20 mm and a thickness of ≤ 5 mm.
- Thin film: Flat sample with a size of ≥ 10 mm to ≤ 20 mm and a substrate thickness of ≤ 4 mm.

 # Advanced analysis - Advanced analysis requires prior discussion or appointment, and physical presence is necessary for the analysis.

****** If the sample(s) present any danger to the personnel or equipment or stipulates any special treatment as protocol, appropriate instruction (s) are to be provided.

Note:

- Please go through the technical details at https://www.cecri.res.in/SAIF/facility.html or contact our Technical Personnel through mail with your requirement before submitting the sample.
- For any specific customized analysis/measurement, the analytical charges can be estimated in consultation with the Business Development section